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Substitute for form 1449A/B/PTO				Complete If Known	
<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>				Application Number	10/734,275-Conf. #1475
(Use as many sheets as necessary)				Filing Date	December 15, 2003
Sheet	1	of	1	First Named Inventor	Kie Y. Ahn
				Art Unit	2826
				Examiner Name	L. Andujar
				Attorney Docket Number	M4065.0383/P383-B

U.S. PATENT DOCUMENTS					
Examiner Initials <sup>1</sup>	Cite No. <sup>1</sup>	Document Number Number-Kind Code <sup>2</sup> (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear

FOREIGN PATENT DOCUMENTS					
Examiner Initials <sup>1</sup>	Cite No. <sup>1</sup>	Foreign Patent Document Country Code <sup>3</sup> -Number <sup>4</sup> -Kind Code <sup>5</sup> (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
					T <sup>6</sup>

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NON PATENT LITERATURE DOCUMENTS					
Examiner Initials <sup>1</sup>	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.			T <sup>2</sup>
<i>W</i>	CA	S. Wolf, Ph.D., et al., "Silicon Processing for the VLSI Era," Chemical Vapor Deposition of Amorphous and Polycrystalline Films, Volume 1, Process Technology, pp. 182-183.			

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Examiner Signature	<i>L. Andujar</i>	Date Considered	10/18/2005
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## INFORMATION DISCLOSURE STATEMENT BY APPLICANT

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### FOREIGN PATENT DOCUMENTS

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Examiner Signature		Date Considered	10/16/2005
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